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Report for Silicon Photonics chip, Process Control Module

Spiral waveguid propagation loss, TE:

Name	Loss	err	Uncertainty	Unit	Polarization
/WG_loss/Q1	16.33	+/-	8.018	dB/cm	TE
/WG_loss/Q2	15.131	+/-	24.476	dB/cm	TE

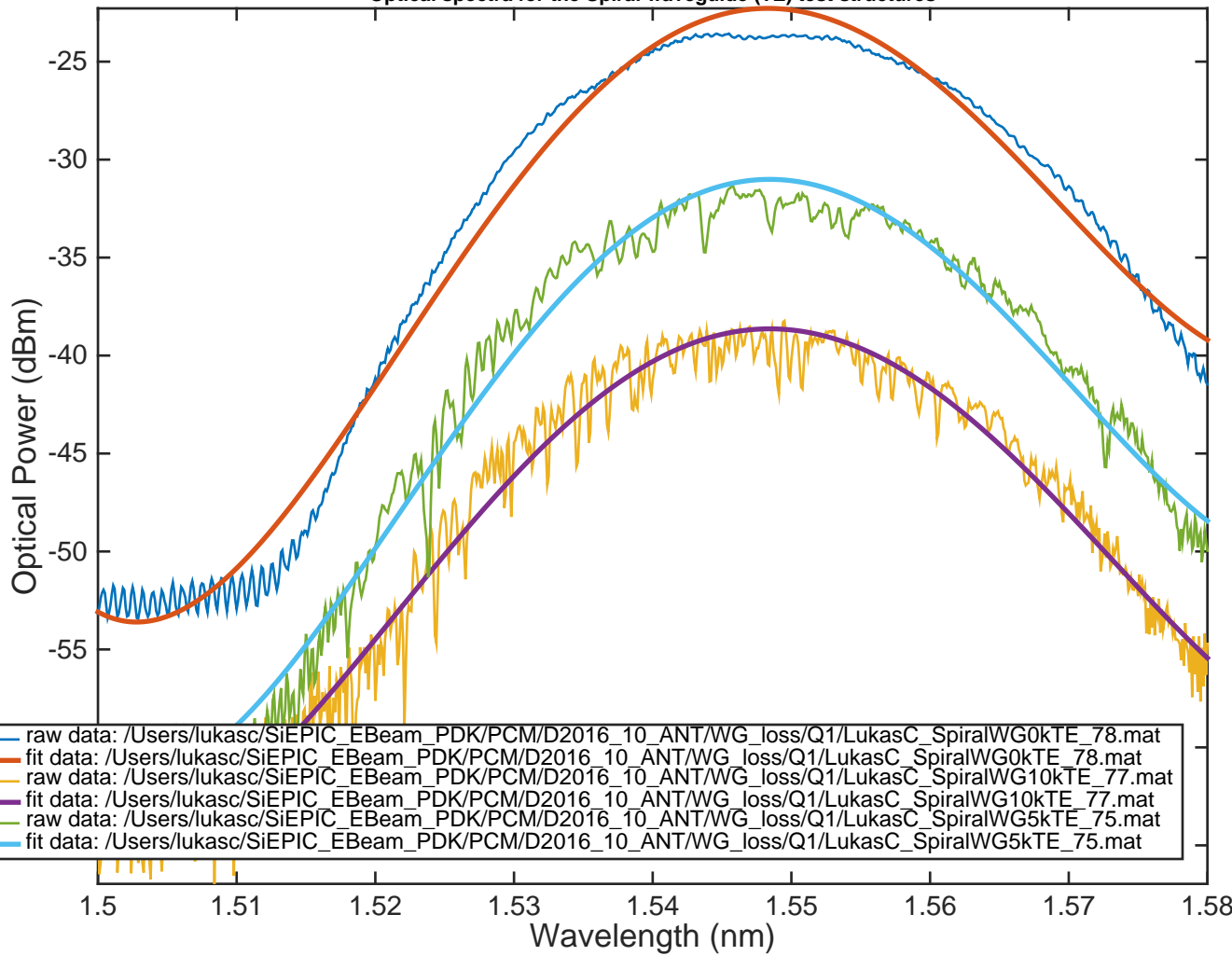
Mean TE: 15.7307 dB/cm

Spiral waveguid propagation loss, TM:

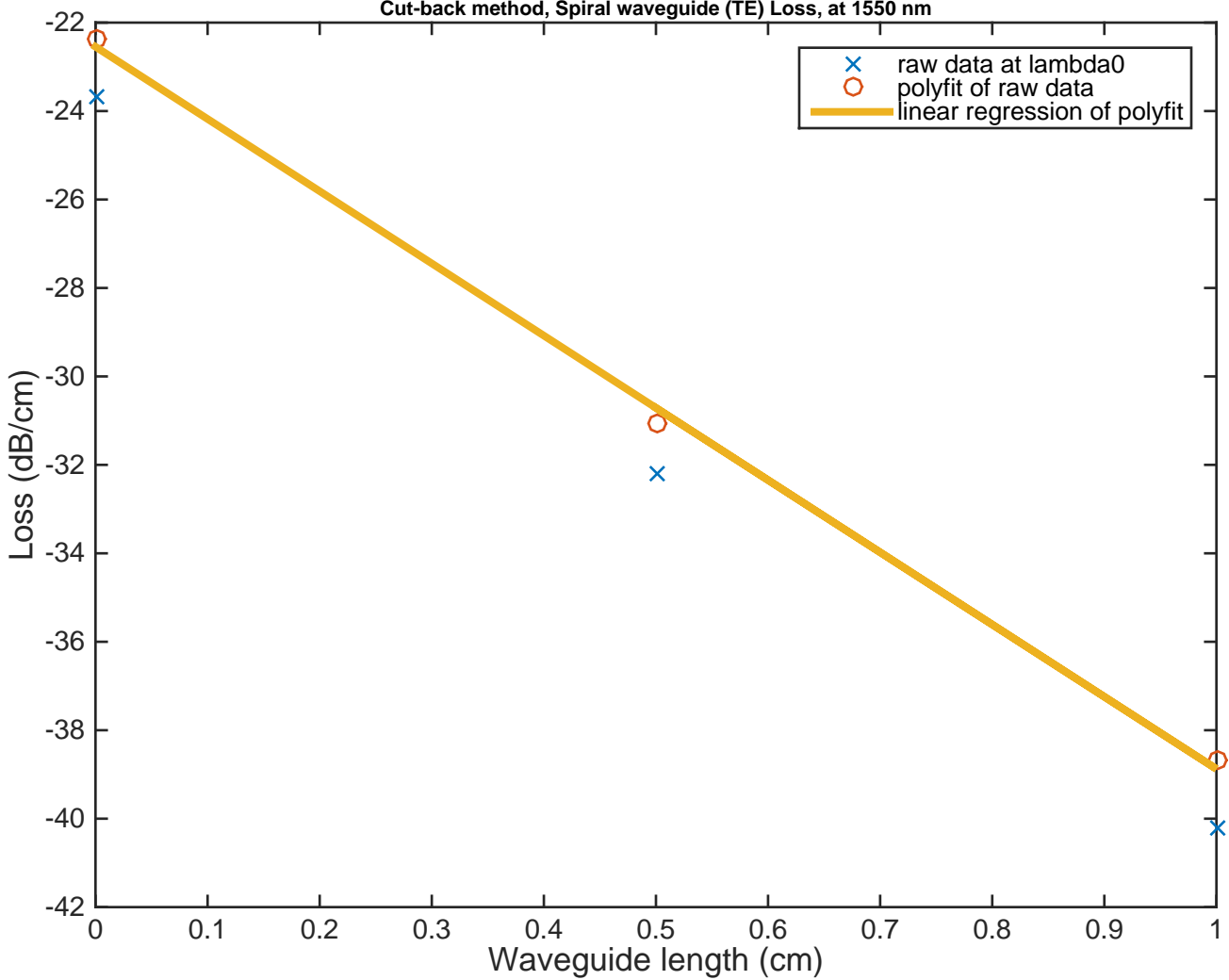
Name	Loss	err	Uncertainty	Unit	Polarization
/WG_loss/Q1	14.611	+/-	9.8948	dB/cm	TM
/WG_loss/Q2	16.563	+/-	6.6325	dB/cm	TM
/WG_loss/Q3	15.042	+/-	3.4571	dB/cm	TM
/WG_loss/Q4	14.415	+/-	21.114	dB/cm	TM

Mean TM: 15.1577 dB/cm

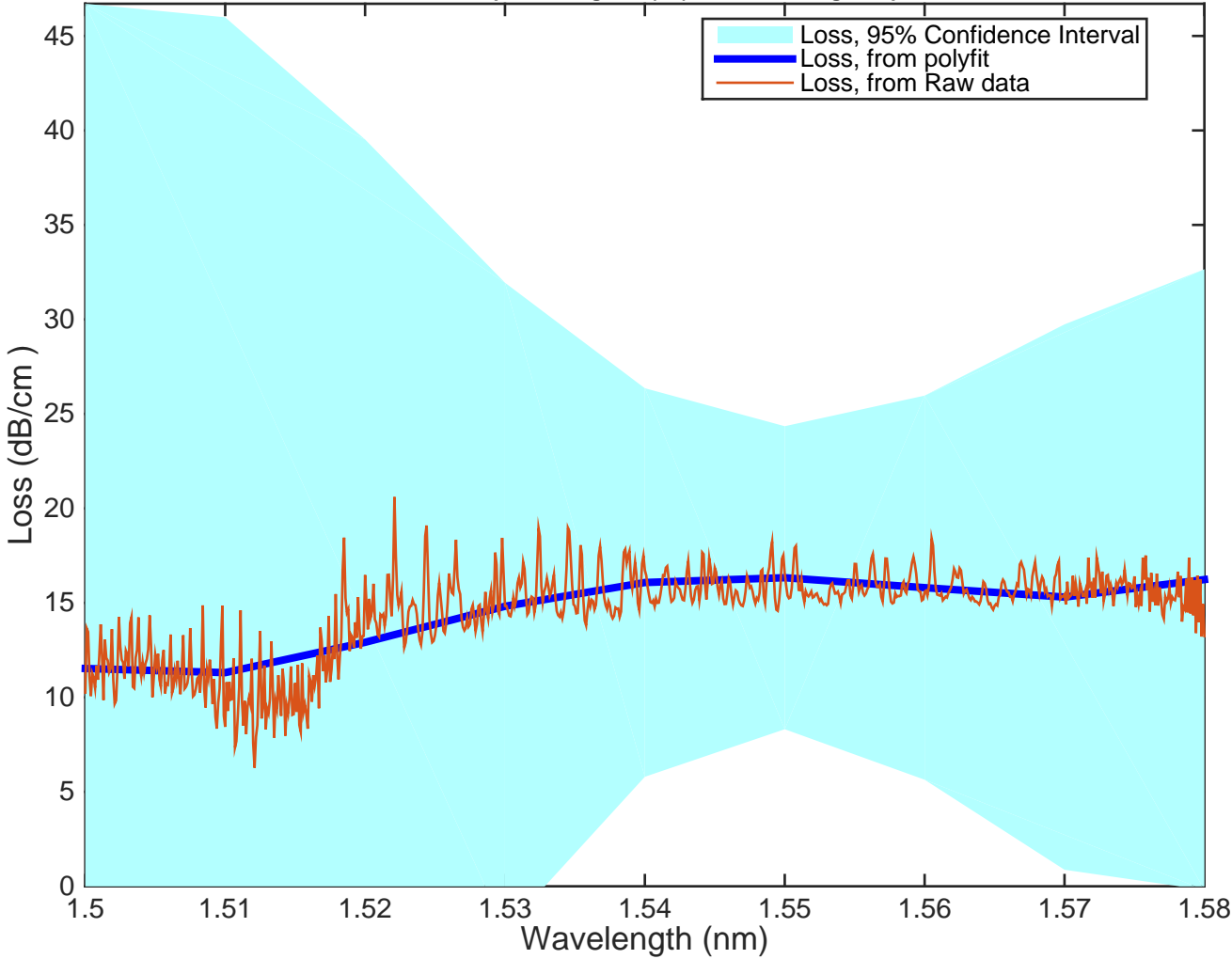
Optical spectra for the Spiral waveguide (TE) test structures



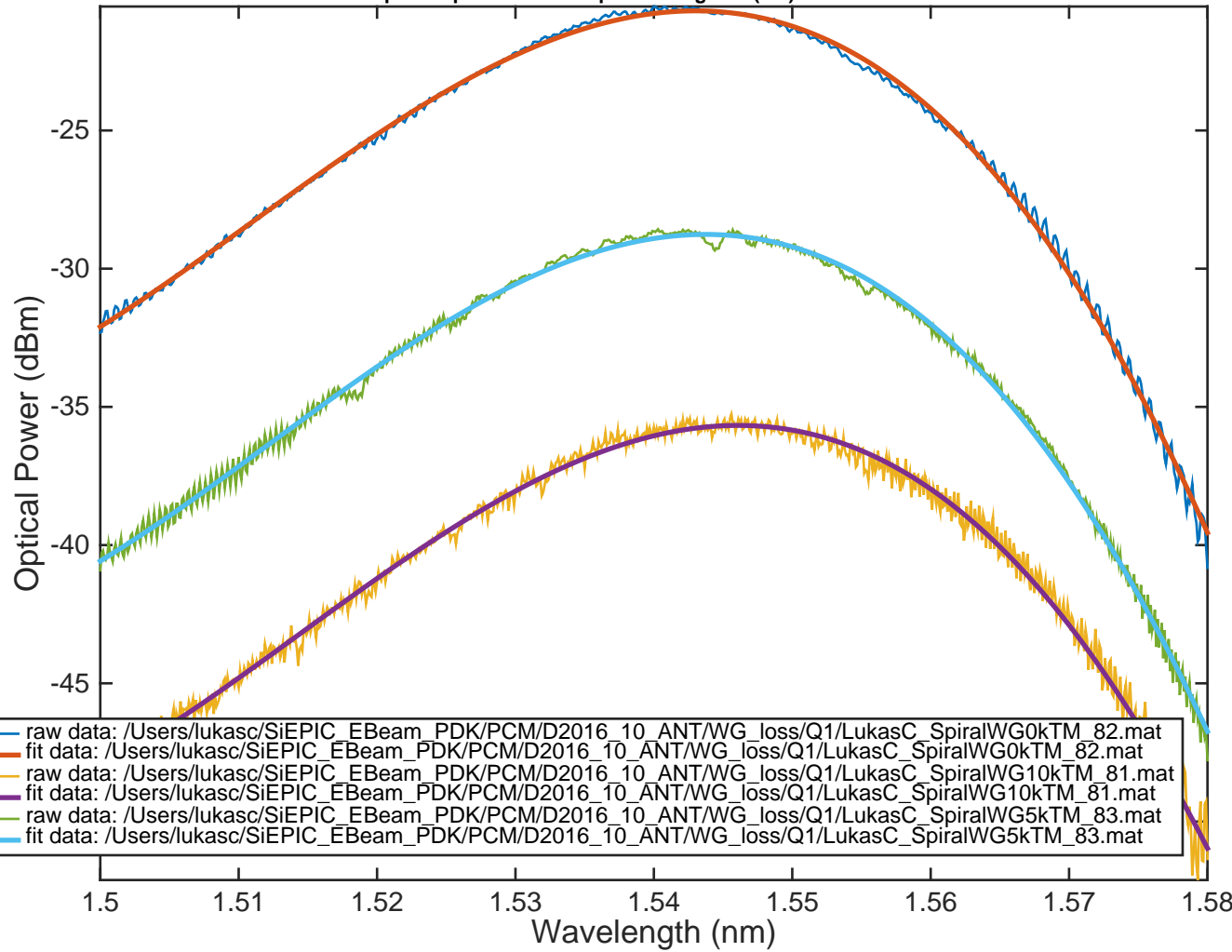
Cut-back method, Spiral waveguide (TE) Loss, at 1550 nm



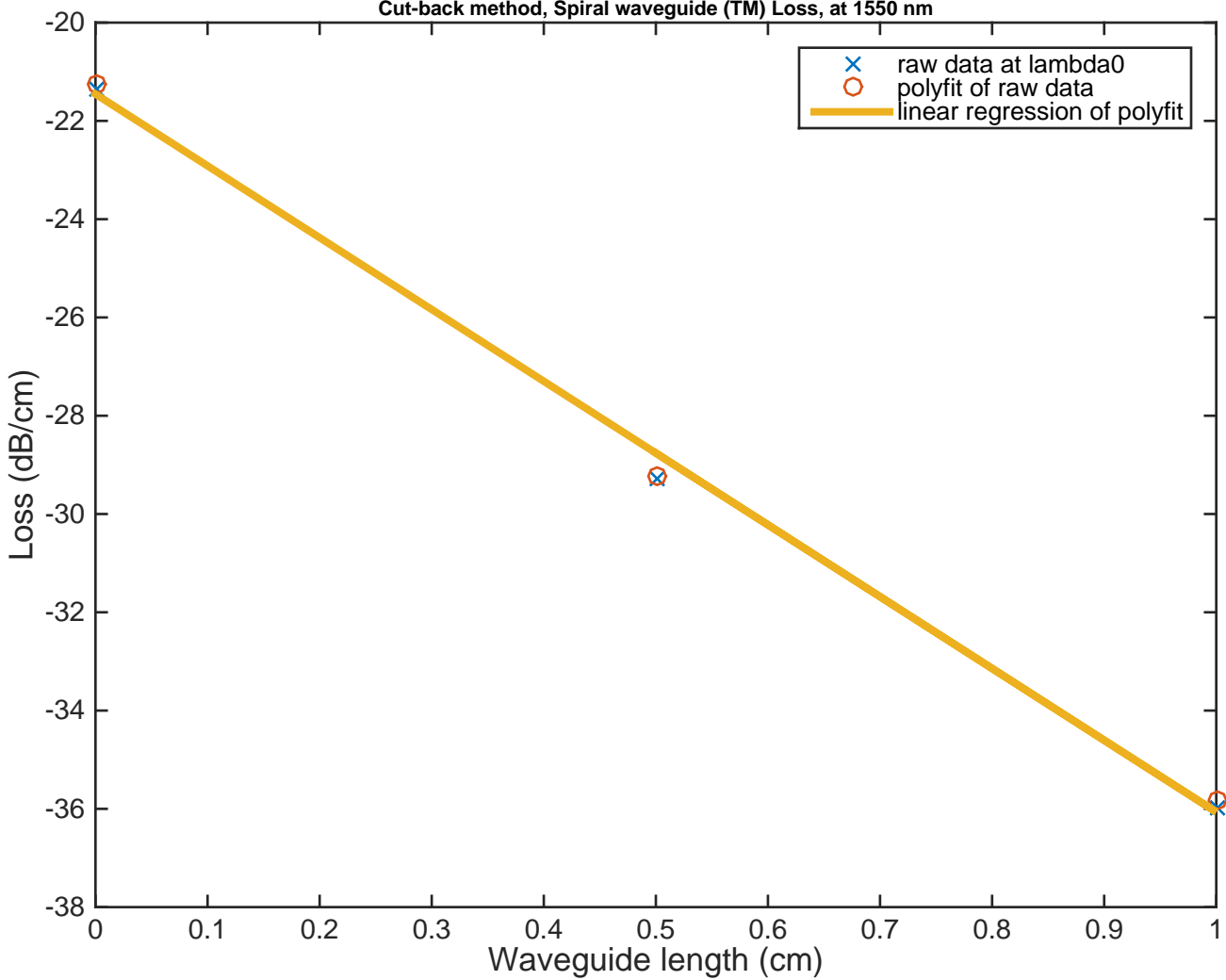
Cut-back method, Spiral waveguide (TE) Loss, wavelength dependence



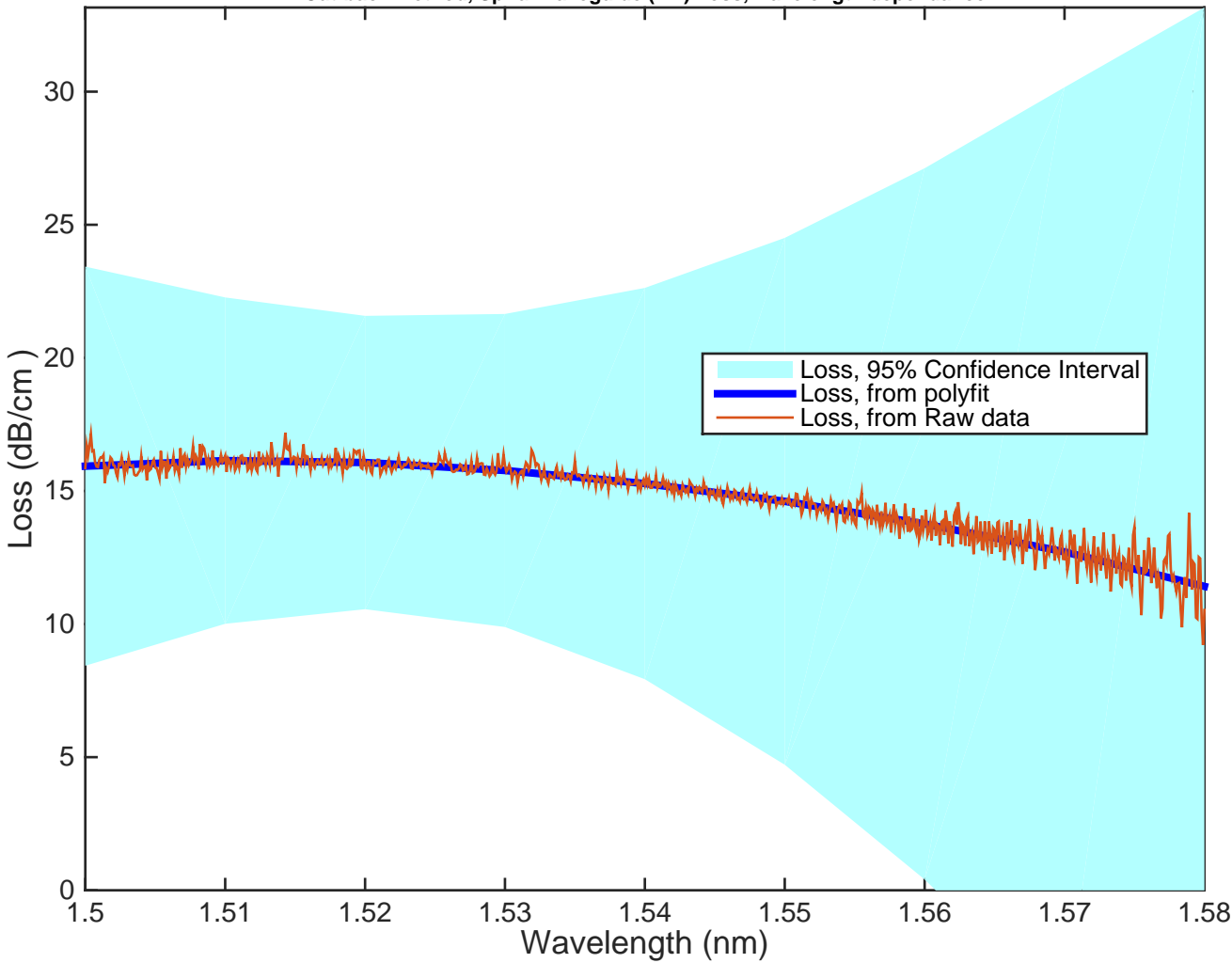
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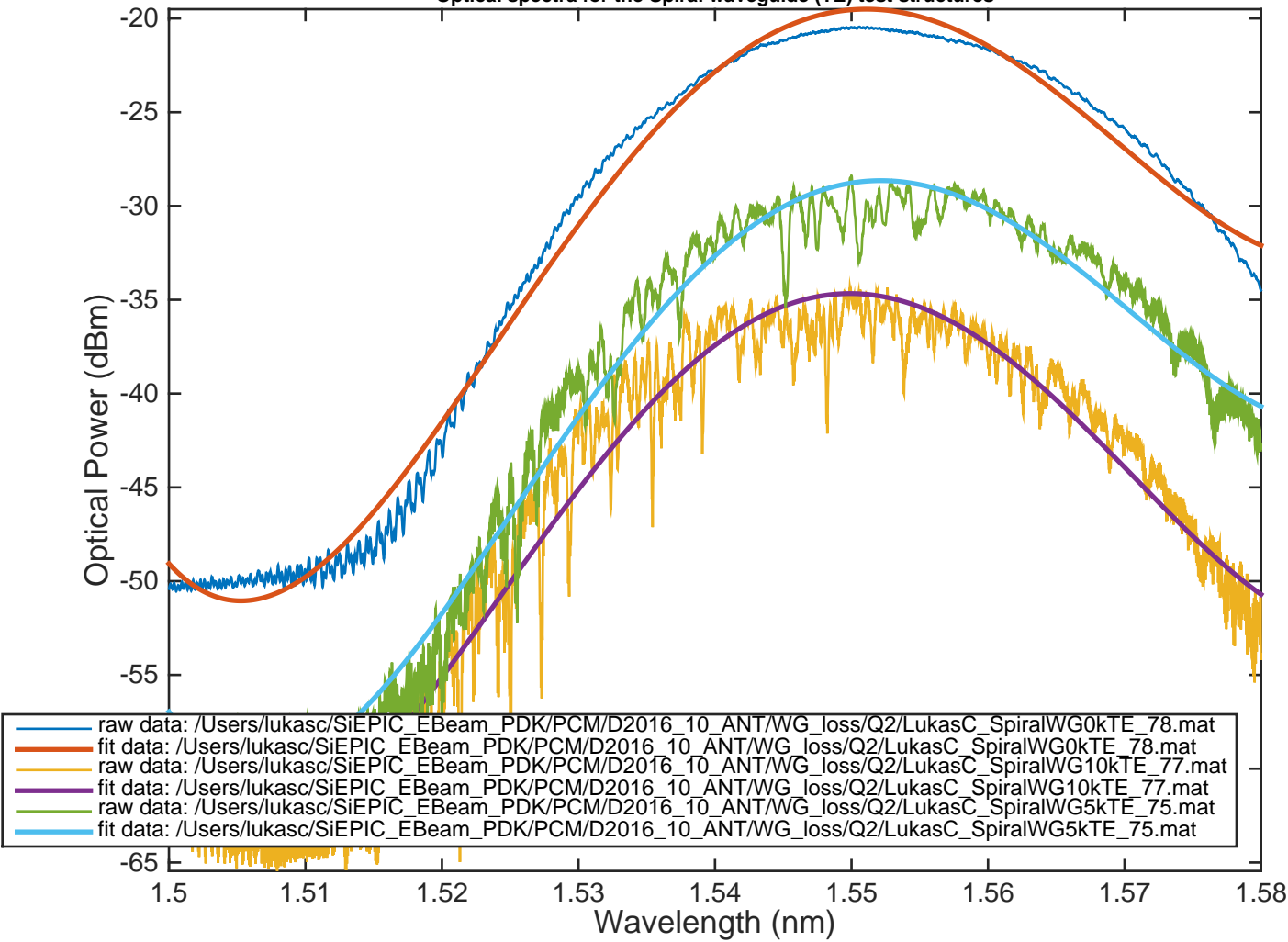
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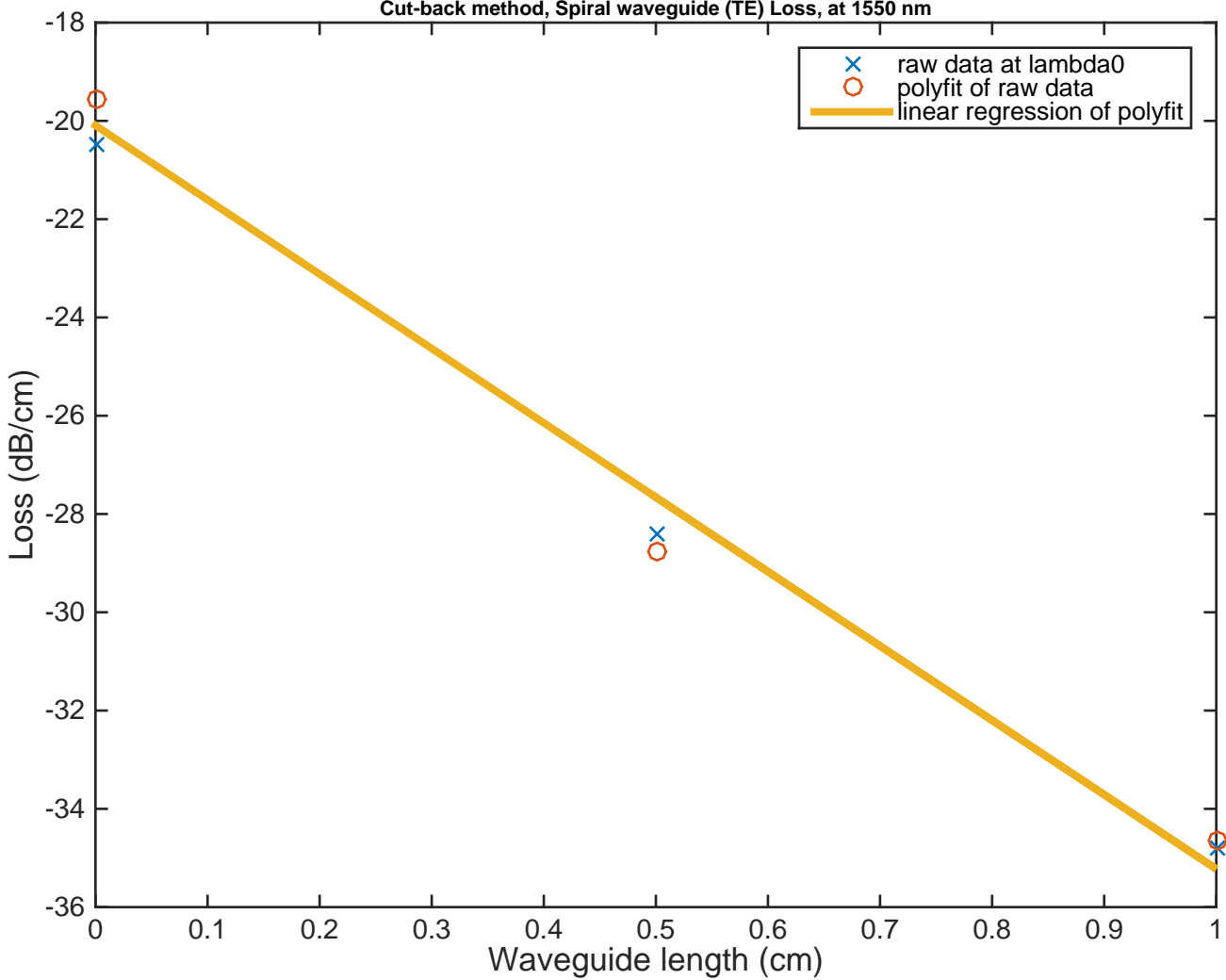
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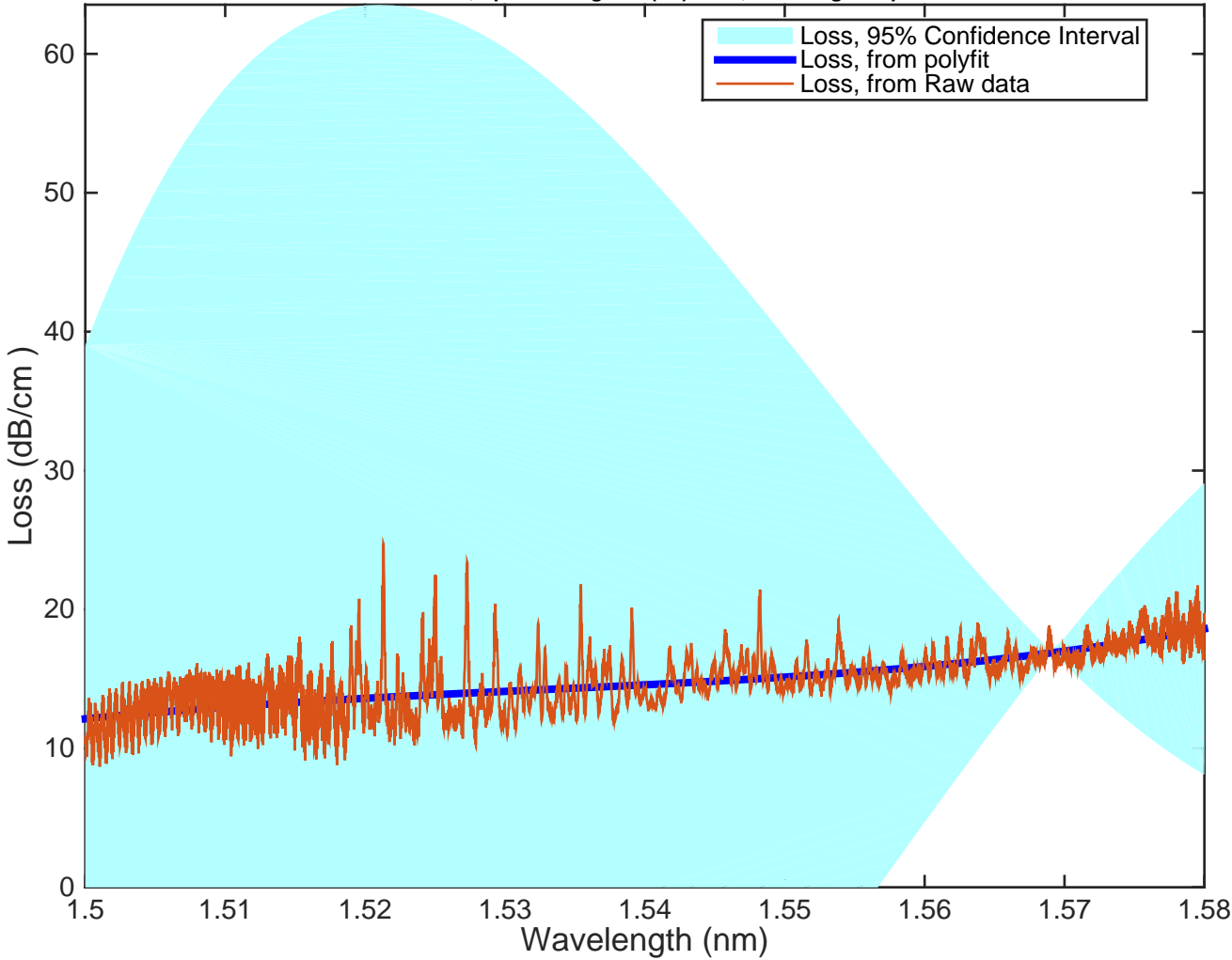
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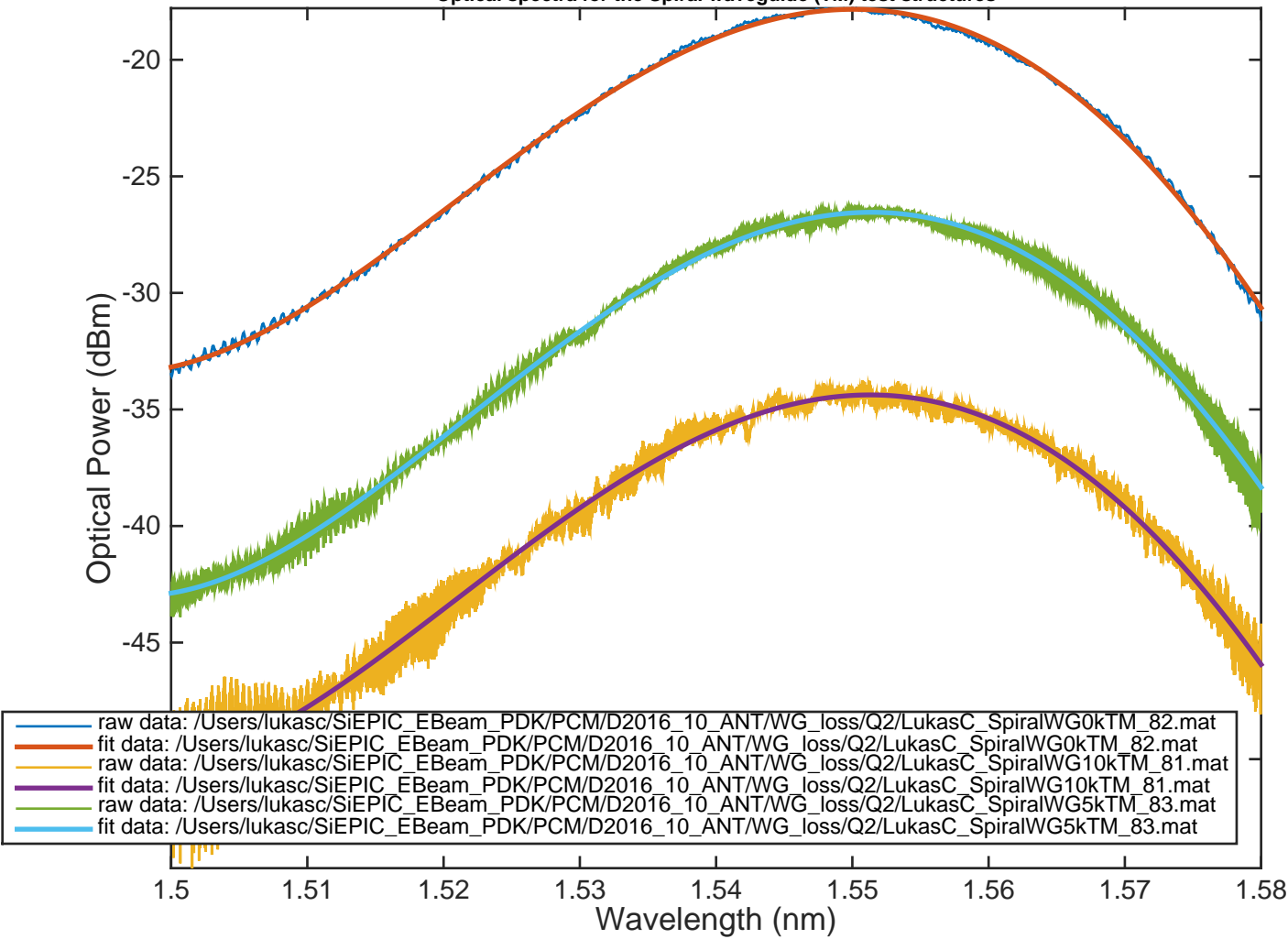
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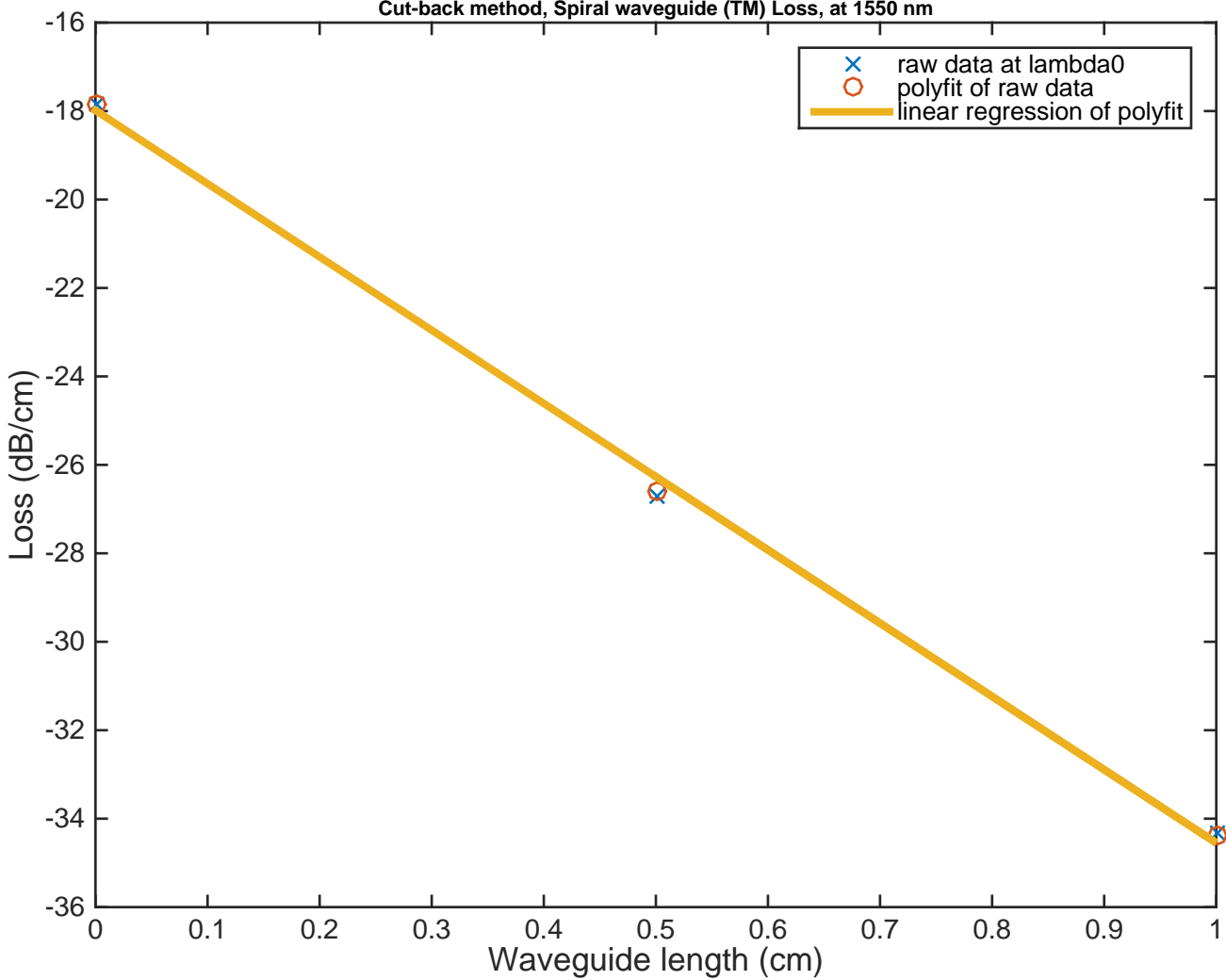
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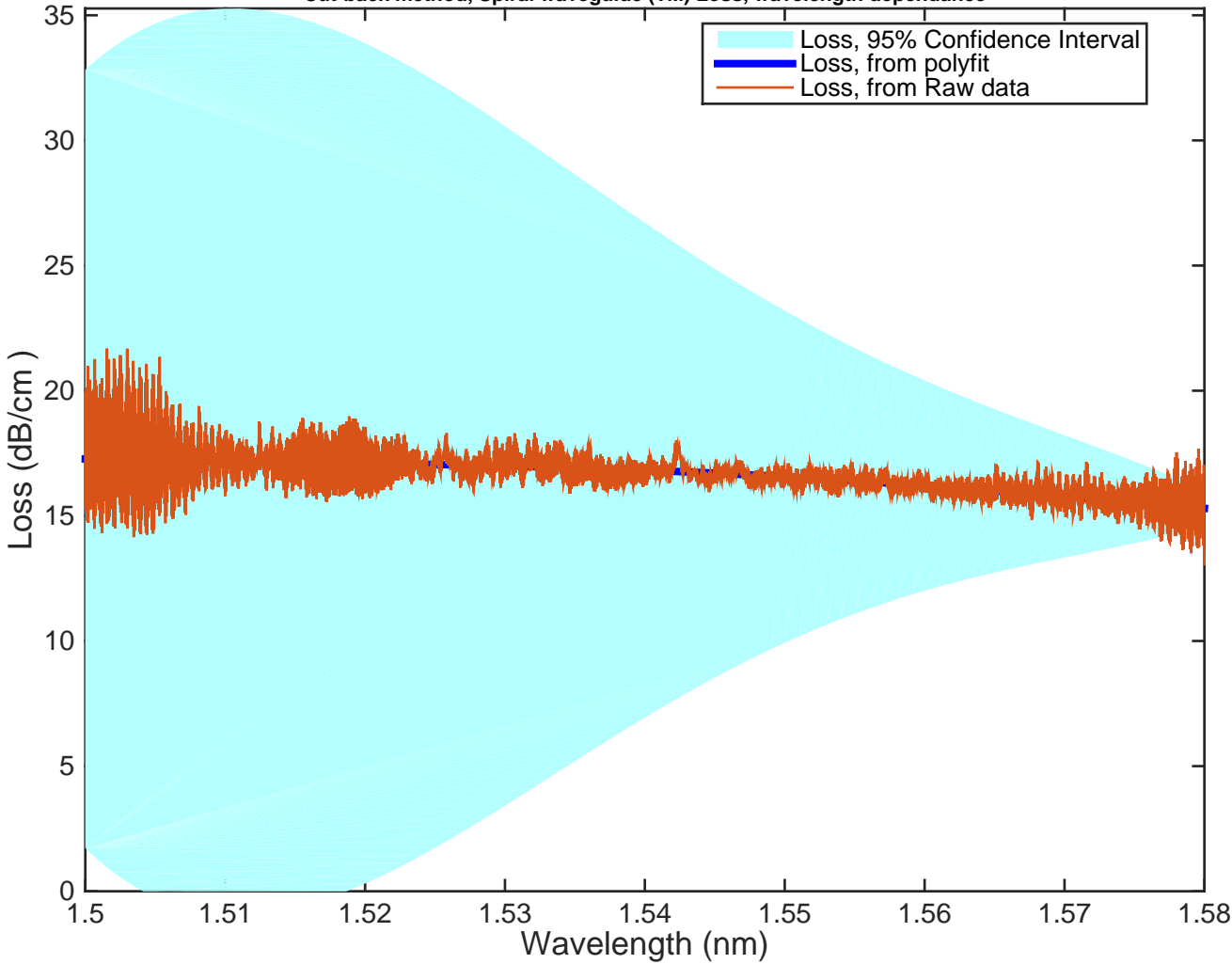
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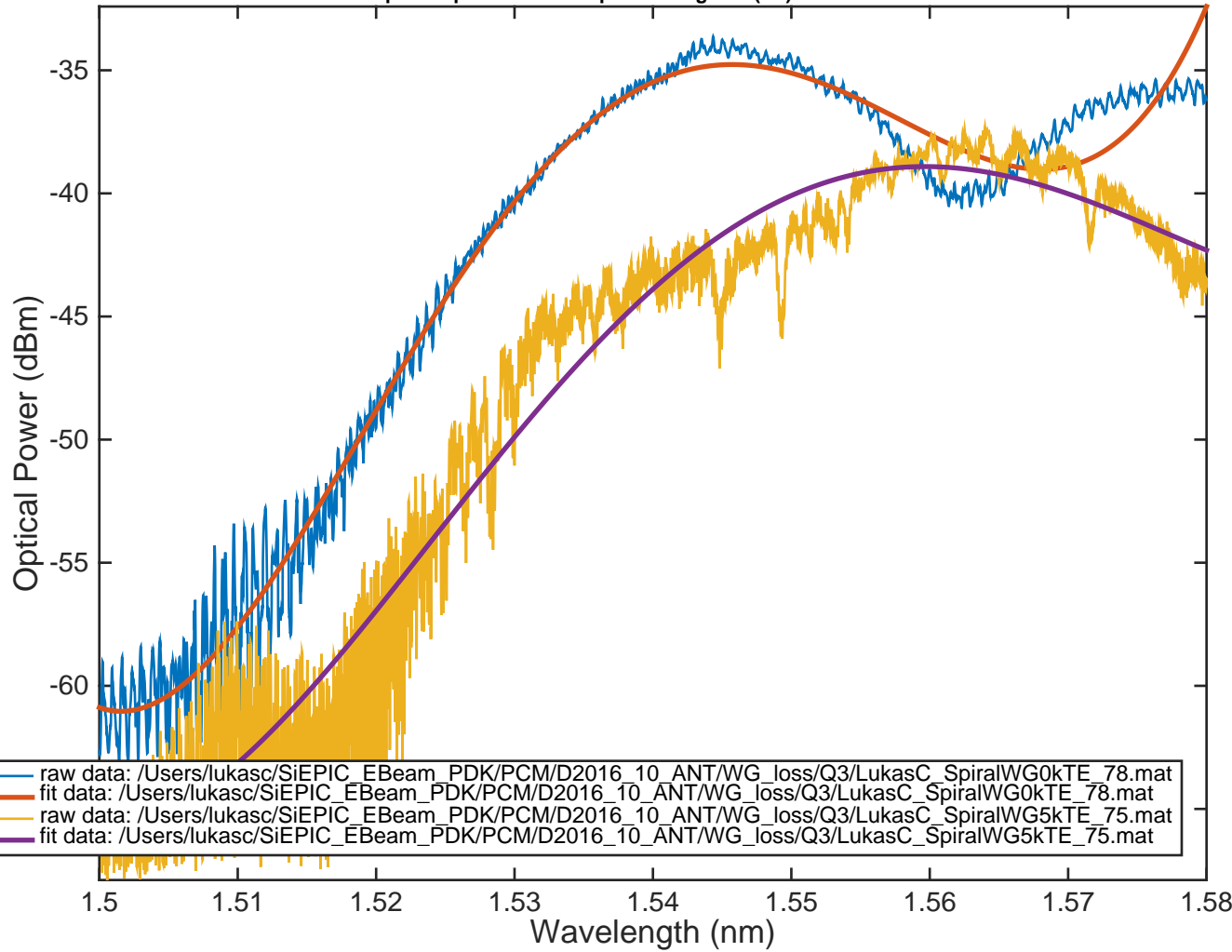
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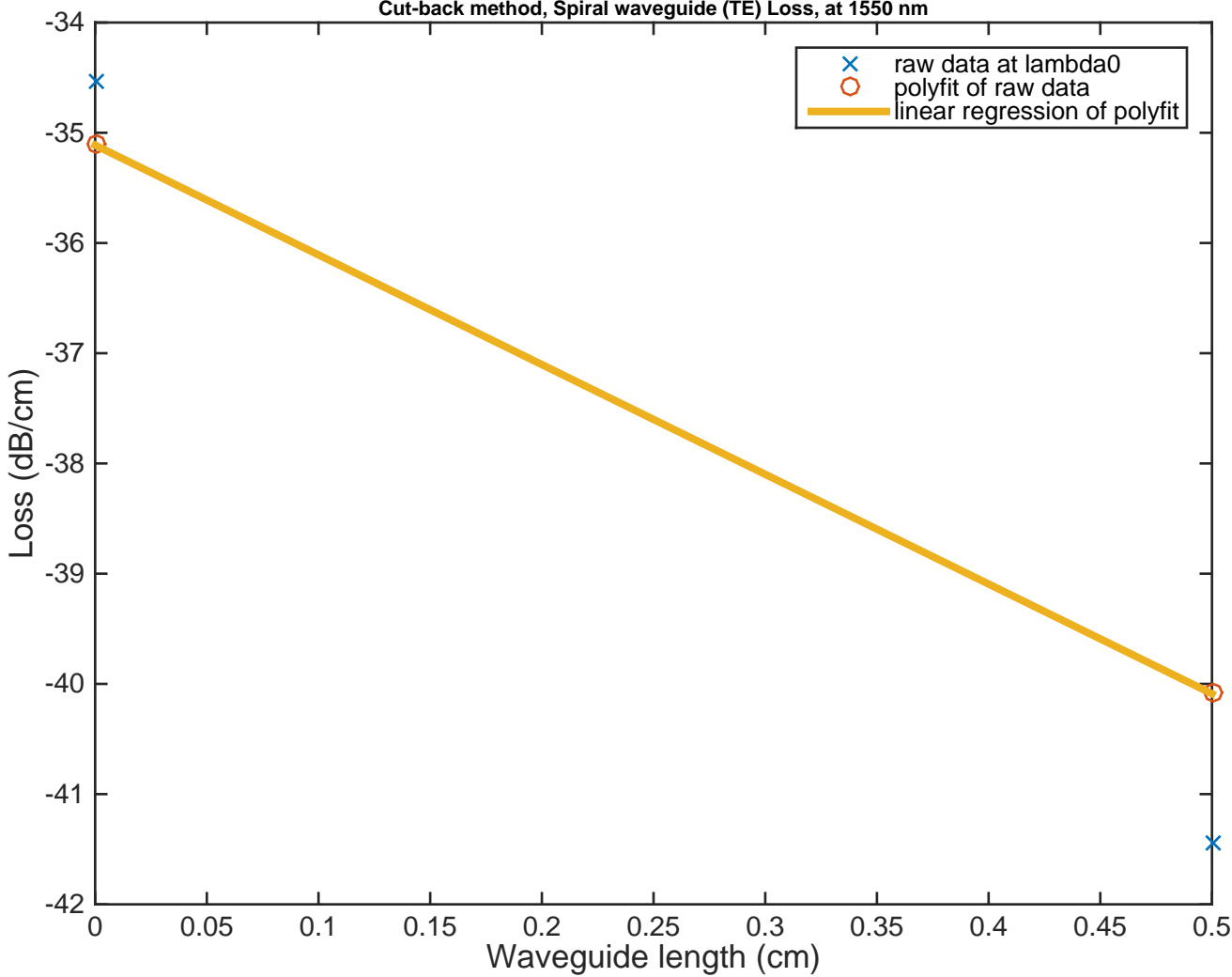
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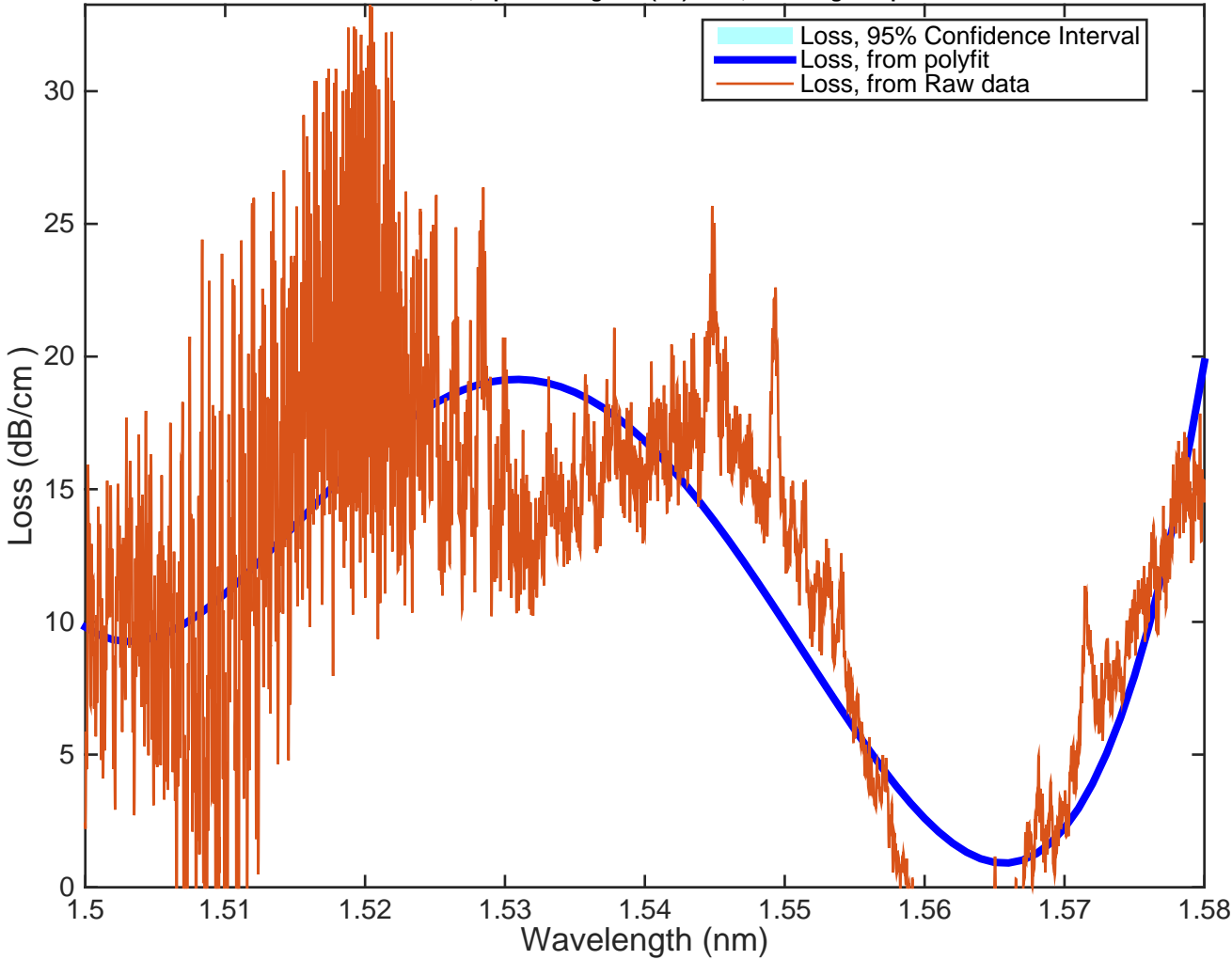
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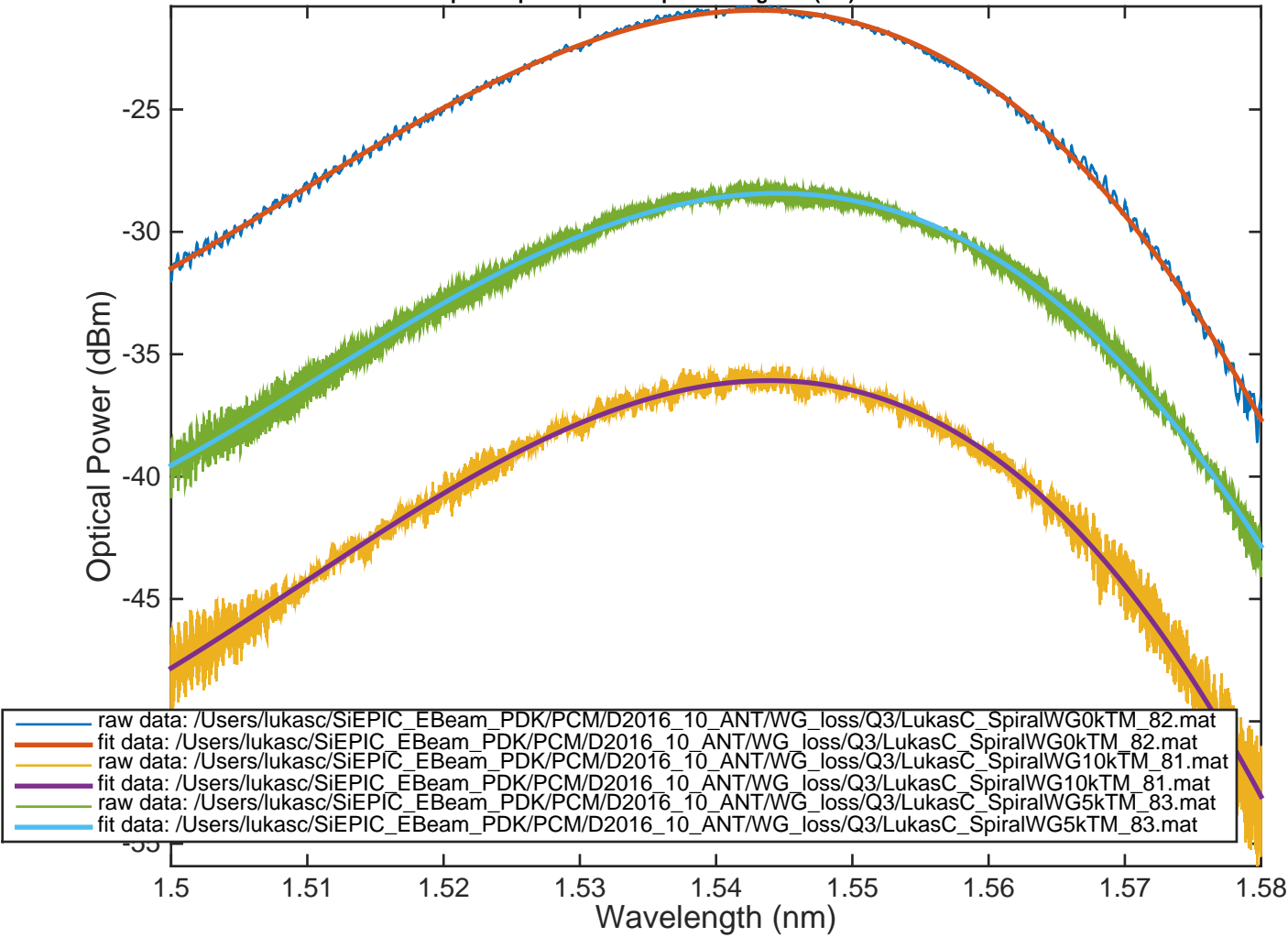
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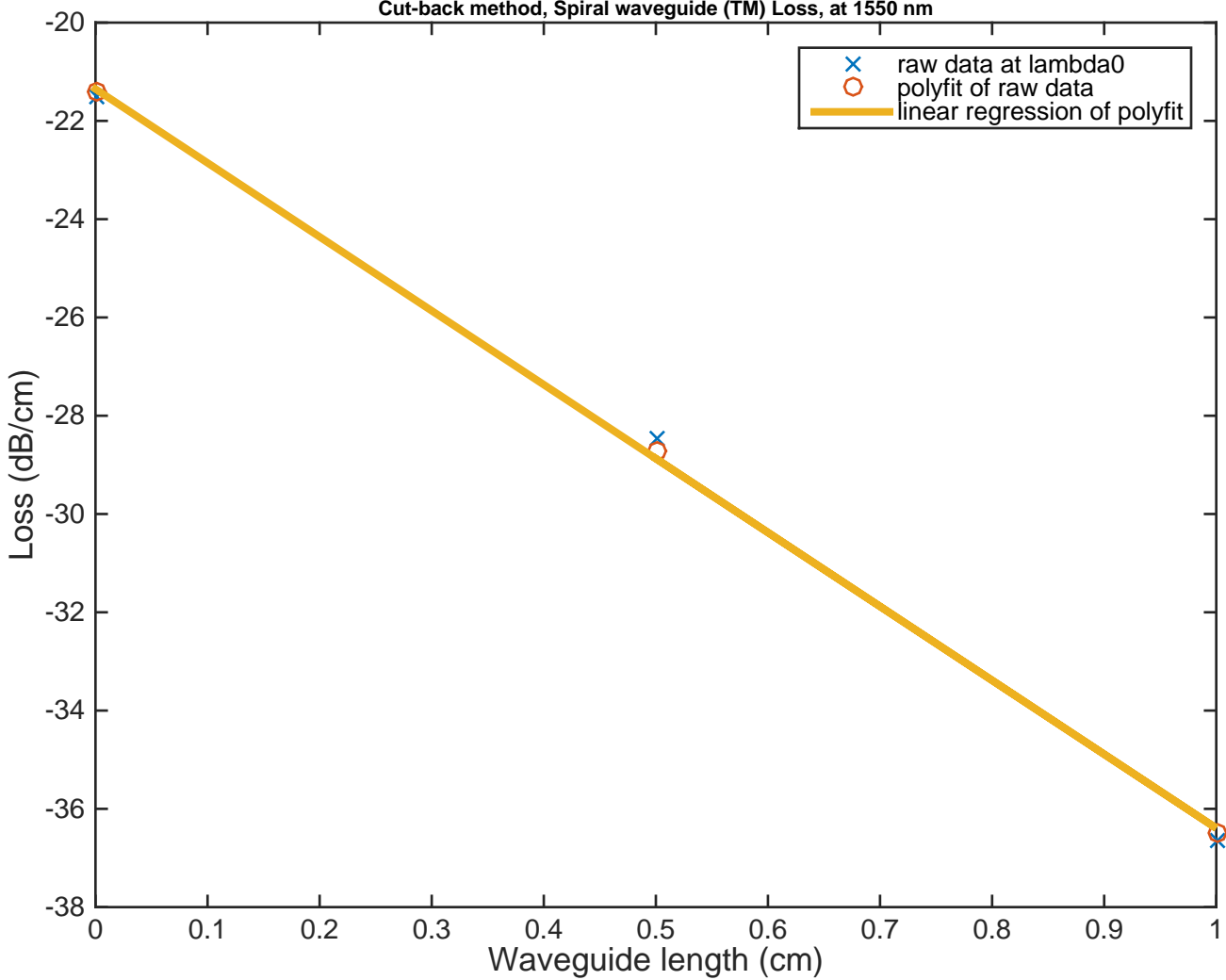
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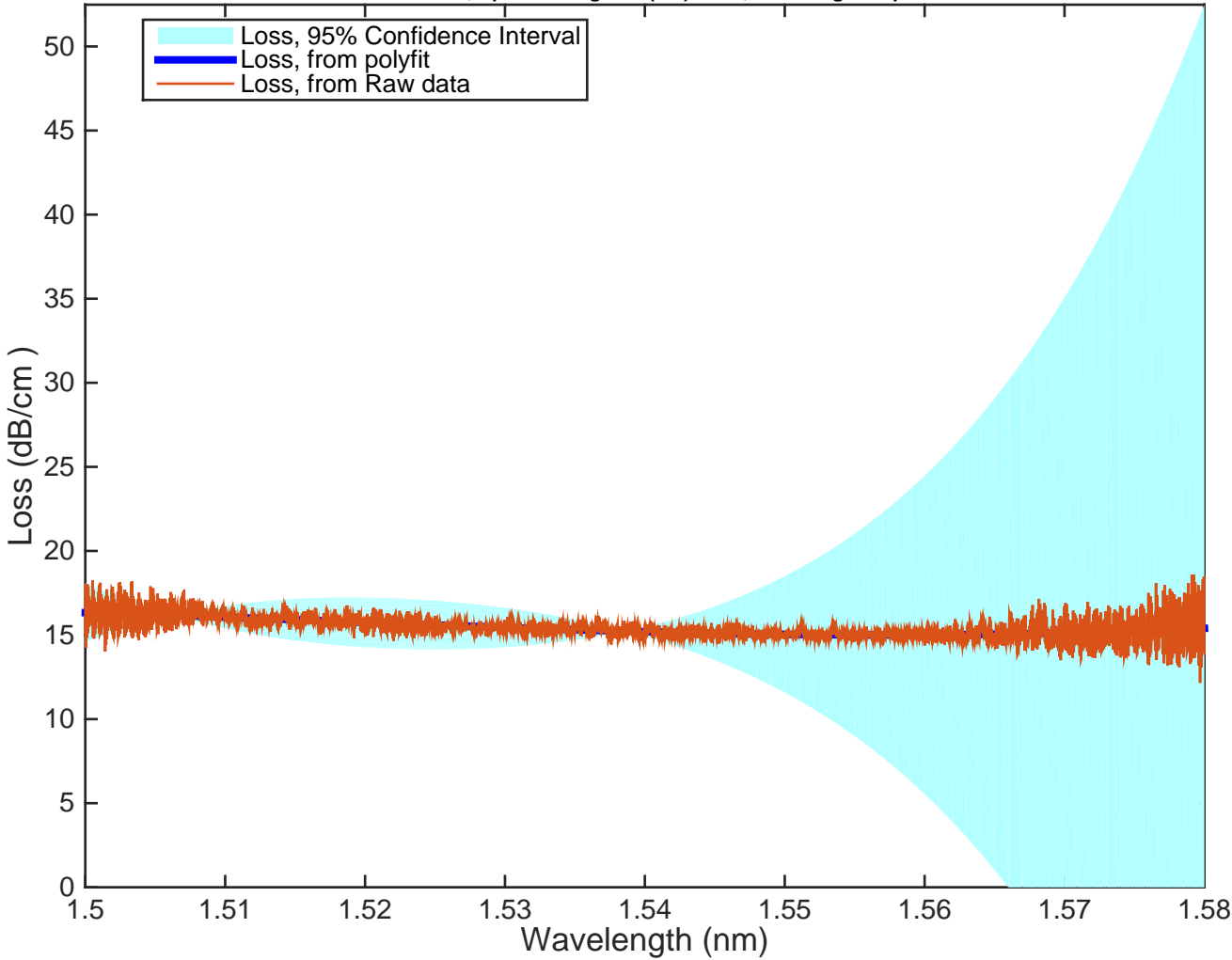
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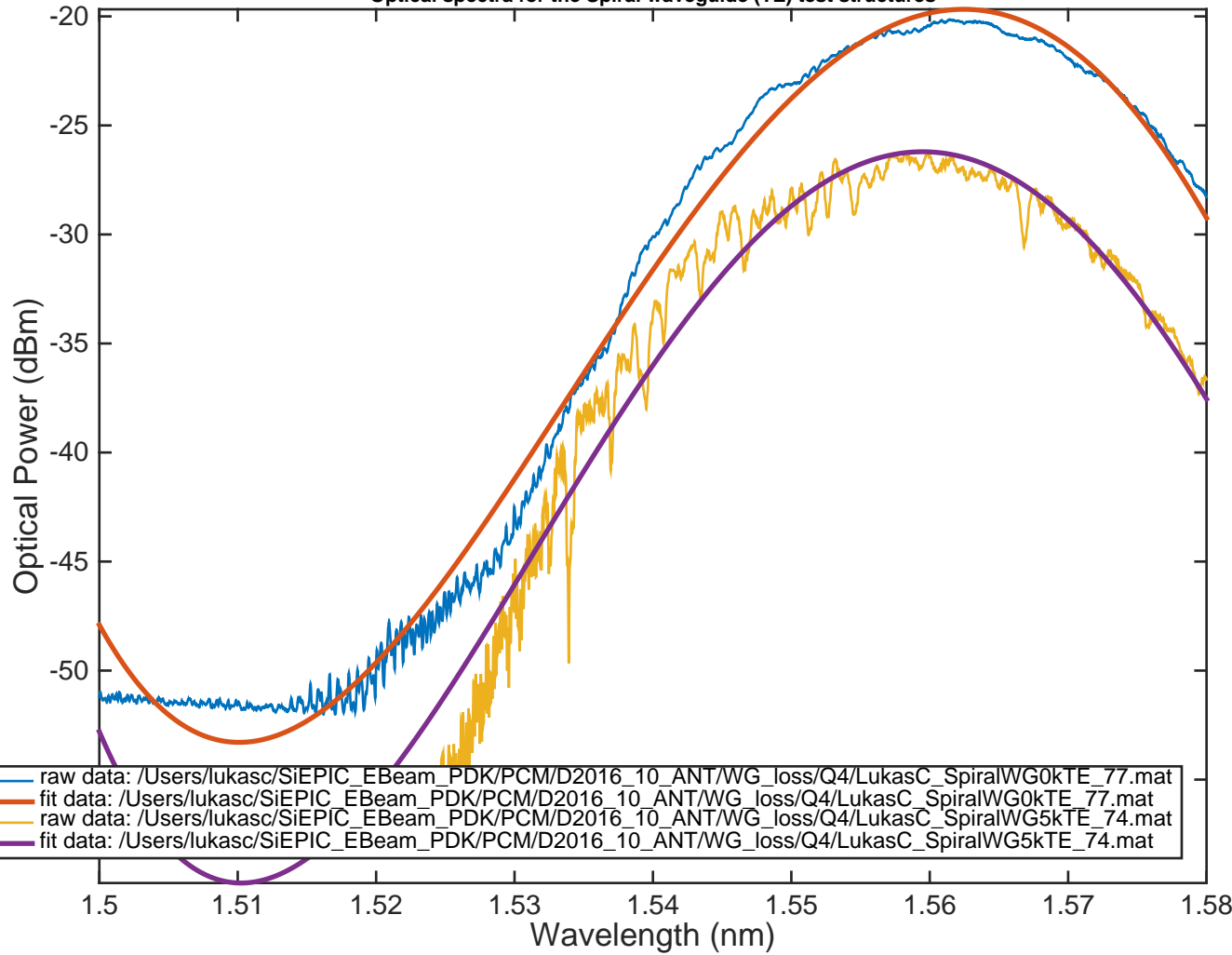
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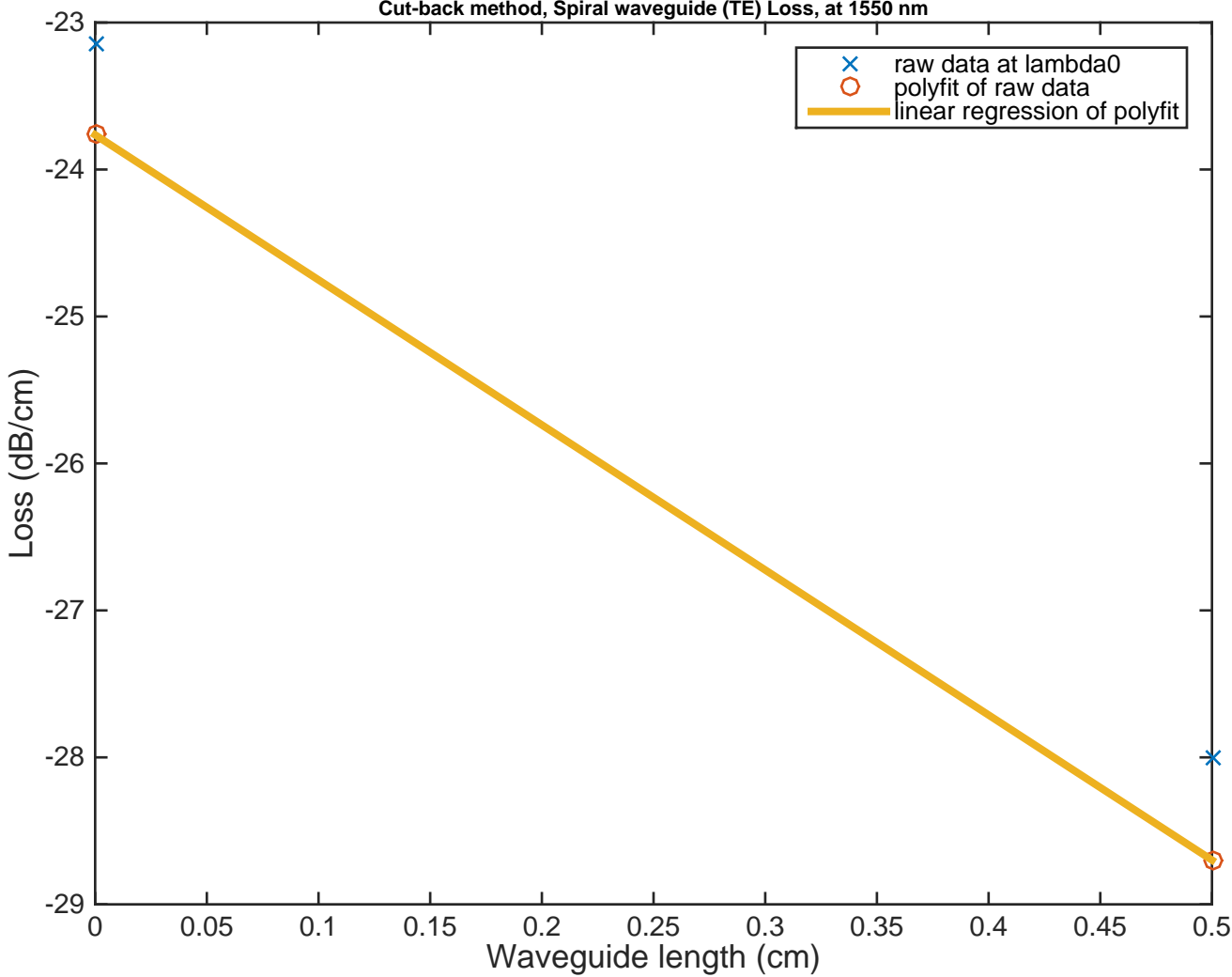
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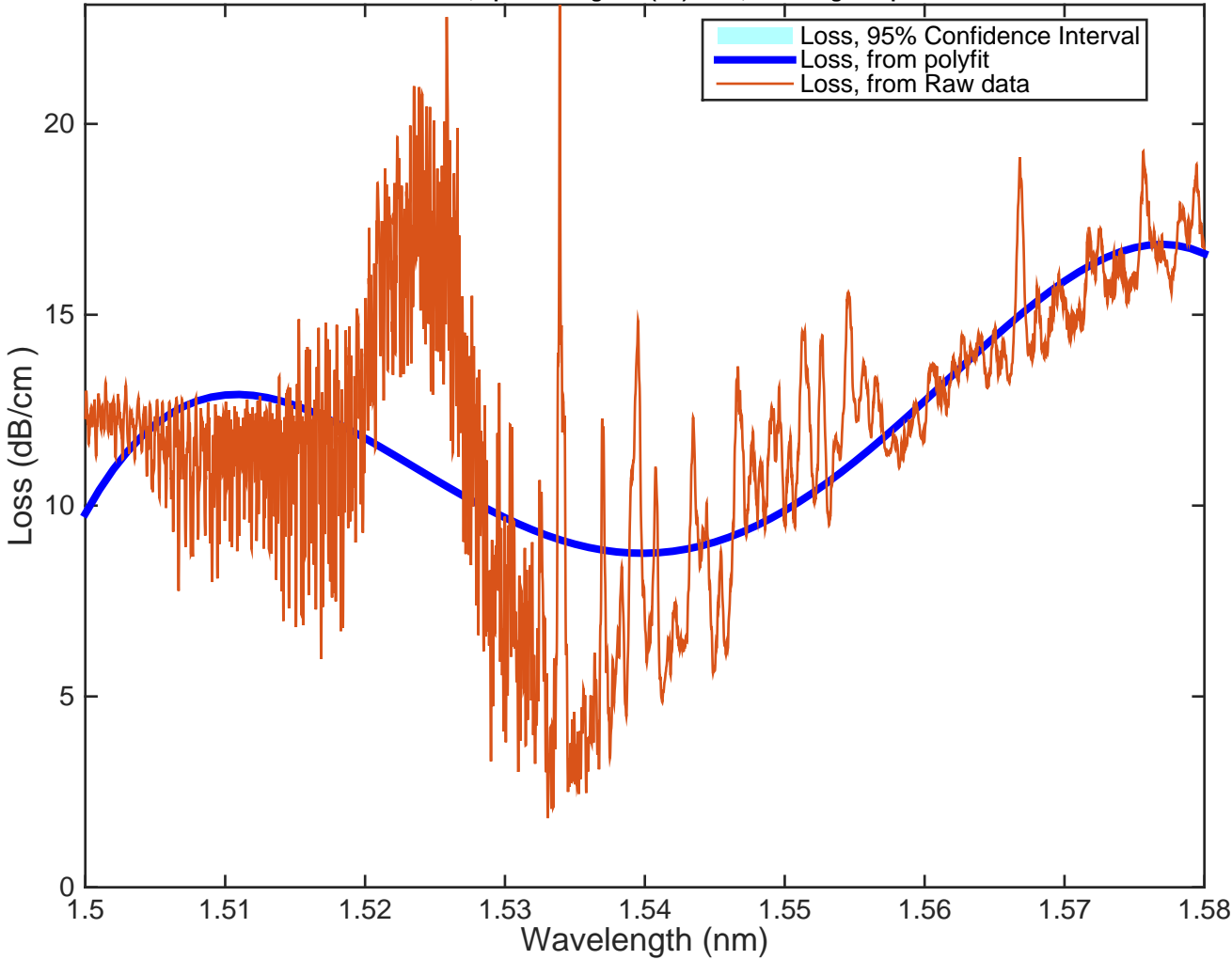
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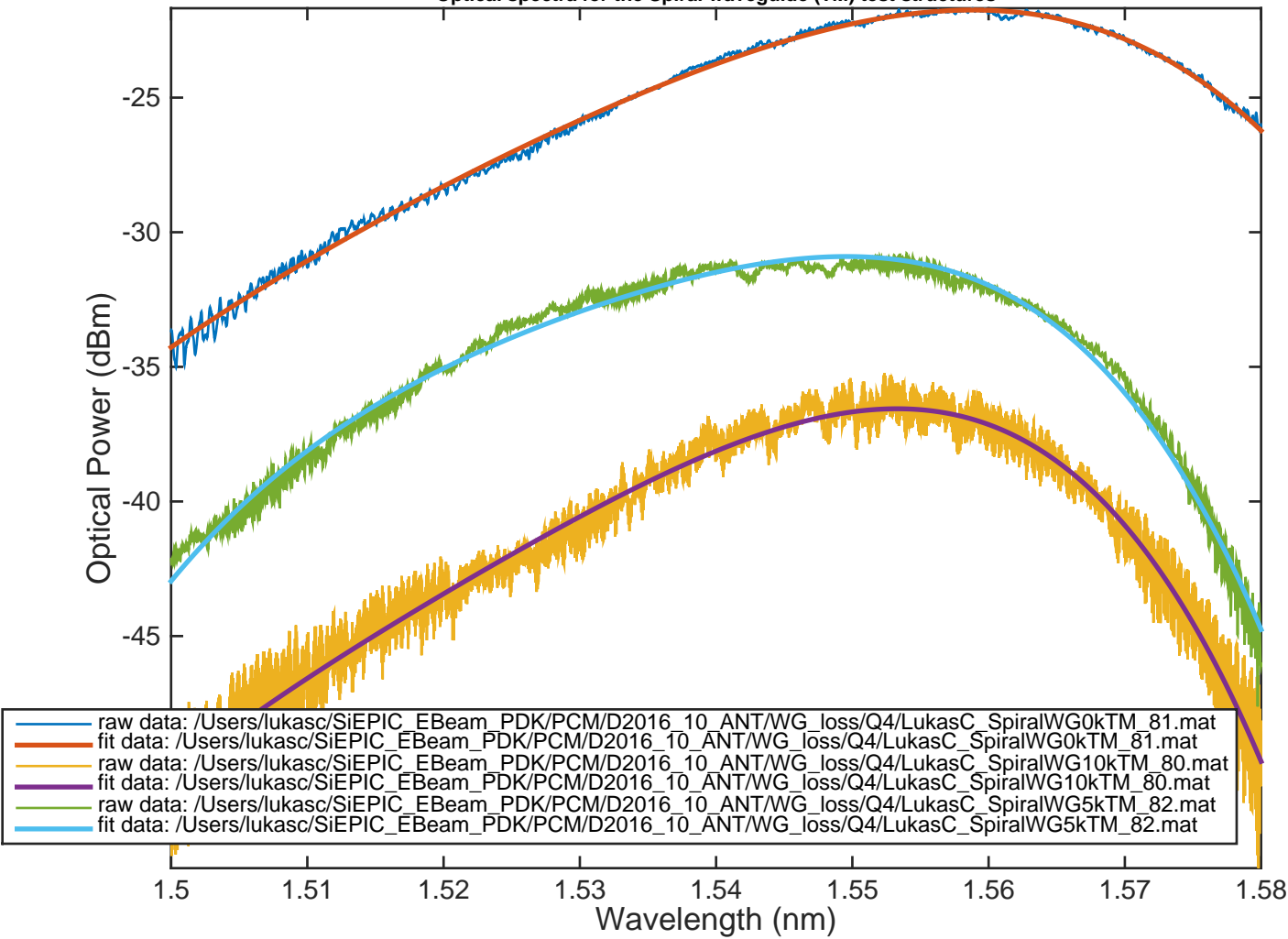
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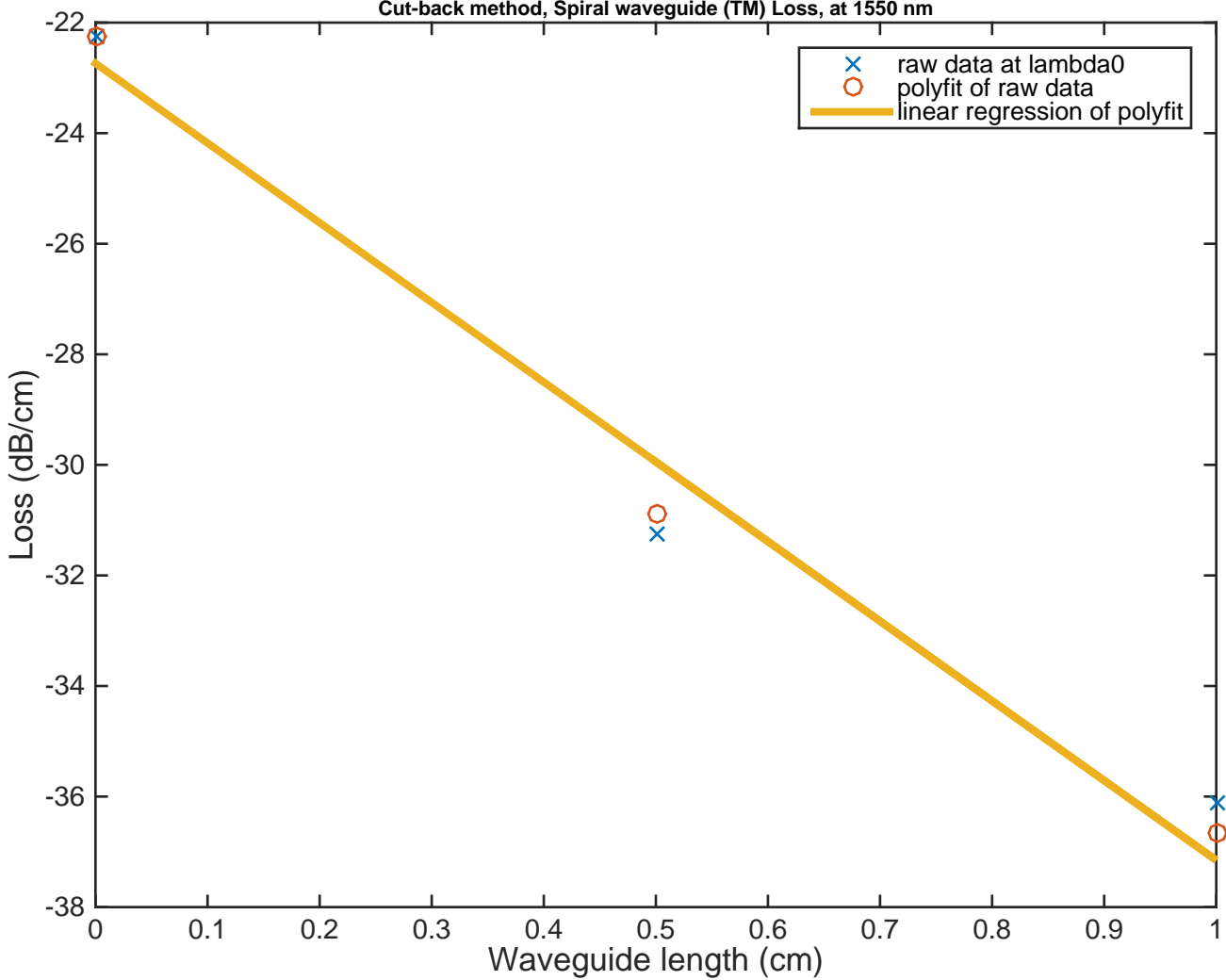
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